Advanced Applications with SAR/PolSAR Images in Earth Observation Task

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Message from the Guest Editors

This Special Issue aims to achieve Earth observation with SAR/PolSAR data, which requires high-quality results in SAR/PolSAR applications. Topics include but are not limited to the following:

- SAR/PolSAR terrain classification;
- SAR/PolSAR object detection and recognition;
- SAR/PolSAR change detection;
- Radar polarimetric theory;
- SAR/PolSAR time-series image analysis;
- SAR/PolSAR image interpretation;
- SAR/PolSAR denoising;
- Deep-learning-based SAR/PolSAR processing.

Special Issue

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Message from the Editor-in-Chief

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